

Notice of References Cited	Application/Control No. 10/568,393	Applicant(s)/Patent Under Reexamination TOKUNAGA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003-286369	10-2003	Japan	Watanabe et al.	C08L 21/00
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JP 2003-286369 (10-2003) abstract and translation in English
	V	
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